Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/731,571	HUFF ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

SEARCHED				
Class	Subclass	Date	Examiner	
713	201	9/19/2005	ECT	
310	329	8/19/2005	ECT	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES, IEEE Explore	8/19/2005	ECT